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*Krawczak, J.; Torok, E.;*

Magnetics, IEEE Transactions on , Volume: 16 , Issue: 5 , Sep 1980  
Pages: 1200 - 1202

[Abstract] [PDF Full-Text (344 KB)] IEEE JNL

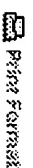
#### 2 Spectral dependences of Faraday rotation in Y3-xBixFe5012LPE films

*Simsa, Z.; Le Gall, H.; Simsova, J.; Kolacek, J.; Le Paillier-Malecot, A.;*

Magnetics, IEEE Transactions on , Volume: 20 , Issue: 5 , Sep 1984  
Pages: 1001 - 1003

[Abstract] [PDF Full-Text (336 KB)] IEEE JNL

#### 3 Effects of some transition metal ions on the visible and infrared Faraday

**rotation of gadolinium iron garnet***Egashira, K.; Manabe, T.;*

Magnetics, IEEE Transactions on , Volume: 8 , Issue: 3 , Sep 1972  
Pages:646 - 648

[Abstract] [PDF Full-Text (320 KB)] IEEE JNL

---

**4 Wide-gap II-VI superlattices**

*Kolodziejski, L.; Gunshor, R.; Otsuka, N.; Datta, S.; Becker, W.; Nurmiiko, A.;*  
Quantum Electronics, IEEE Journal of , Volume: 22 , Issue: 9 , Sep 1986  
Pages:1666 - 1676

[Abstract] [PDF Full-Text (4368 KB)] IEEE JNL

---

**5 High-selectivity single-chip spectrometer in silicon for operation in visible part of the spectrum**

*Correia, J.H.; Bartek, M.; Wolfenbuttel, R.F.;*  
Electron Devices, IEEE Transactions on , Volume: 47 , Issue: 3 , March 2000  
Pages:553 - 559

[Abstract] [PDF Full-Text (1060 KB)] IEEE JNL

---

**6 Sun and view angle corrections on reflectances derived from NOAA/AVHRR data**

*Leroy, M.; Roujean, J.-L.;*  
Geoscience and Remote Sensing, IEEE Transactions on , Volume: 32 , Issue: 3 , May 1994  
Pages:684 - 697

[Abstract] [PDF Full-Text (1196 KB)] IEEE JNL

---

**7 Polar Kerr rotation in Co-doped hexagonal ferrites**

*Simsa, Z.; Gornert, P.; Poynton, A.J.; Gerber, R.;*  
Magnetics, IEEE Transactions on , Volume: 26 , Issue: 5 , Sep 1990  
Pages:2789 - 2791

[Abstract] [PDF Full-Text (180 KB)] IEEE JNL

---

**8 Optical properties of high- $T_c$  superconductors**

*Aspnes, D.E.; Kelly, M.K.;*  
Quantum Electronics, IEEE Journal of , Volume: 25 , Issue: 11 , Nov. 1989  
Pages:2378 - 2387

[Abstract] [PDF Full-Text (884 KB)] IEEE JNL

**9 Optical power calibrator based on a stabilized green He-Ne laser and a cryogenic absolute radiometer**

*Varpula, T.; Seppa, H.; Saari, J.-M.;*  
Instrumentation and Measurement, IEEE Transactions on , Volume: 38 , Issue: 2 , Apr 1989  
Pages:558 - 564

[Abstract] [PDF Full-Text (688 KB)] IEEE JNL

**10 Visible and near-infrared laser emission of pigment extracted from green algae in microdroplet mixed with highly scattering Intralipid-10%**

*Taniguchi, H.; Tanosaki, S.; Devaraj, B.; Inaba, H.;*  
Electronics Letters , Volume: 33 , Issue: 21 , 9 Oct. 1997  
Pages:1797 - 1798

[Abstract] [PDF Full-Text (204 KB)] IEE JNL

**11 Assimilating LANDSAT data in an ecosystem model for multi-year simulation of grassland carbon, water and energy budget**

*Nouvellon, Y.; Moran, M.S.; Chehbouniz, A.; Lo Seen, D.; Bryant, R.; Nichols, M.;*  
*Prevot, L.; Rambal, S.; Ni, W.; Begue, A.; Heilman, P.; Keefer, T.O.;*  
Geoscience and Remote Sensing Symposium, 2000. Proceedings. IGARSS 2000. IEEE 2000 International, Volume: 5 , 24-28 July 2000  
Pages:1966 - 1968 vol.5

[Abstract] [PDF Full-Text (276 KB)] IEEE CNF

**12 Modified Soil Adjusted Crop Residue Index (MSACRI): a new index for mapping crop residue**

*Bannari, K.; Haboudane, D.; McNairn, H.; Bonn, F.;*  
Geoscience and Remote Sensing Symposium, 2000. Proceedings. IGARSS 2000.

IEEE 2000 International , Volume: 7 , 24-28 July 2000  
Pages:2936 - 2938 vol.7

[Abstract] [PDF Full-Text (236 KB)] IEEE CNF

---

**13 Discrimination of Africa's vegetation using reconstructed ERS-1 imagery**  
*Hardin, P.J.; Long, D.G.; Remund, Q.P.;*  
Geoscience and Remote Sensing Symposium, 1996. IGARSS '96. 'Remote Sensing  
for a Sustainable Future.', International , Volume: 2 , 27-31 May 1996  
Pages:827 - 829 vol.2

[Abstract] [PDF Full-Text (312 KB)] IEEE CNF

---

**14 Automated training sample labeling using laboratory spectra**  
*Hsieh, P.; Landgrebe, D.A.;*  
Geoscience and Remote Sensing Symposium, 1996. IGARSS '96. 'Remote Sensing  
for a Sustainable Future.', International , Volume: 3 , 27-31 May 1996  
Pages:1855 - 1857 vol.3

[Abstract] [PDF Full-Text (336 KB)] IEEE CNF

---

**15 Measuring the frequency of light with ultrashort pulses**  
*Haensch, T.W.;*  
Lasers and Electro-Optics, 2001. CLEO '01. Technical Digest. Summaries of papers  
presented at the Conference on , 6-11 May 2001  
Pages:507 - 508

[Abstract] [PDF Full-Text (208 KB)] IEEE CNF

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